Paper ID 28 SFDR Improvement Algorithm for Current-Steering DACs

Shaiful Nizam Mohyar*,

H. Hassan, M. Murakami, A. Motozawa, H. Kobayashi,
O. Kobayashi, T. Matsuura, N. Takai, I. Shimizu,
K. Niitsu, M. Tsuji, M. Watanabe, N. Dobashi,
R. Shiota, S. Umeda, T. J. Yamaguchi

Gunma University, Japan

Universiti Malaysia Perlis, Universiti Teknologi MARA, Malaysia Nagoya University, STARC, Japan

Gunma University, Japan

- Introduction
- Switching-Sequence Post-Adjustment (SSPA)
- One-Element-Shifting (OES)
- SSPA & OES Combination
- Simulation Result
- Conclusion

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Introduction

Background

- Telecommunication devices
 - > Mobile phones, wireless modems & avionics
 - > High-speed, high-accuracy DAC!!!
- Application
 - Transmitters
 - > Interference reduction
 - > High SFDR performance
- Our approach

Digital rich for high SFDR DAC

DAC – Digital-to-Analog Converter SFDR – Spurious Free Dynamic Range

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Spurious Free Dynamic Range (SFDR)

Degradation sources

- Data-dependent switching transients
 - Temporal disturbance
- Data-dependent output load variations
 - Output impedance change



Objective & Investigated Method

• Objective

- ♦ High SFDR
 - >Mismatch effect reduction
 - Low glitch

Proposed method

- Current source mismatches
 - Switching-Sequence Post-Adjustment (SSPA)
- Glitch effect

One-Element-Shifting (OES) Dynamic nonlinearity SSPA & OES Combination

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Design Approach

Analog

- Complex hardware
- Not programmable
- Expensive (production & testing)

Digital

- Simple
- Programmable
- Low-cost

Digital rich approach for fine CMOS implementation





Current-steering DAC (CS DAC)





CS DAC limitation

Transistor mismatch

- Current source mismatch
- Source of timing errors

• Mismatch among current cells

Causing DAC static & dynamic non-linearity

Better transistor matching

- ♦ Big size ➔ Power loss
- ◆ Laid out close to each other → Complicated

Binary versus Unary CS DAC

SW3

SW6

SW2

R

R

SW2

SW1

Vout

SW1

Binary

- ♦ Small silicon area ☺
- High sampling speed ⁽²⁾
- Large glitch energy 8
- ♦ No redundancy ⊗



- ♦ Small glitch energy ☺
- Redundancy 🙂
- Large silicon area 8

SW7

Vout

Segmented CS DAC



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Current Source Mismatch



➔ DAC nonlinearity ⊗!!!

Nonlinearity & SFDR degradation



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What is Glitch?

• Main causes

Non-ideal switching behavior
 between two consecutive update steps

➔ MAJOR!!!

- Signal feedthrough
 - gate-drain capacitances
- Static timing uncertainty between two different current cells
- Asymmetric up & down output characteristics

Glitch by non-ideal switch





Unary 🗲 Small glitch 🙂, Current source mismatch 😕

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Why SSPA

- Post-fabrication
 - non-linearity improvement
- Small additional circuits
 - Current comparator (DSP inside SoC)
- Simple implementation
- Require extra current sources
 - Replacement \rightarrow defect / worst mismatch
- Complicated wiring

SSPA Operation



Data-dependent output 8!!!

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TC Operation



Why OES

- Change data-dependent to data-independent
 - Disturbance reduction
- Glitch as small as in TC
 - ➔ Low-power
- Simple implementation

OES Operation



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SSPA & OES Combination



SSPA – Switching-Sequence Post-Adjustment OES –One Element Shifting Gunma University, Japan

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SFDR Performance



SFDR Performance vs Mismatch



Glitch



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SSPACES — Switching-Sequence Post-Adjustment & One Element Shifting Combination TC – Thermometer-code

Comparison

fin = 1.433MHz, fs = 4.096MHz, 10-bit σ : 6% , min:-20%, max:-20%

| Algorithm | SFDR (dBFS) | SFDR (dBc) | Diff (dB) | Switching Occurrences | Diff (%) |
|------------------------|----------------|---------------|--------------|--------------------------|-------------|
| СТС | 61.3 | 58.3 | + 24.0 | 2376311 | + 0.18 |
| OES | 63.3 | 60.3 | + 22.1 | 2380181 | + 0.02 |
| SSPACTC | 83.8 | 80.7 | + 1.6 | 2376311 | + 0.18 |
| Proposed (SSPA+OES) | 85.4 | 82.4 | - | 2380692 | - |

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Conclusion

- Proposed method
 - ♦ SSPA → Mismatch-induced distortion reduction
 - ♦ OES → Data-dependent distortion suppression
- Simulation result SSPAOES combination
 - ♦ >20 dB SFDR compared to conventional TC
 - Comparable small glitch energy to conventional TC

Thank you very much for your kindly attention

Presented by Shaiful Nizam Mohyar



Question & Answer

